

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/520,028	<b>Applicant(s)/Patent under Reexamination</b> NAKAGAWA ET AL.
	<b>Examiner</b> Leila Malek	<b>Art Unit</b> 2611

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	2/12/2008	L.M.
IEEE	2/12/2008	L.M.
GOOGLE	2/12/2008	L.M.

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner